IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the application of:	)
	) Group Art Unit: 1746
Boyd et al.	)
	) Examiner: Unassigned
Application No. 10/606,022	)
	) Atty. Docket No.: LAM2P425
Filed: June 24, 2003	)
	) Date: January 19, 2005
For: SYSTEM AND METHOD FOR	)
INTEGRATING IN-SITU METROLOGY WITHIN	)
A WAFER PROCESS	)

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
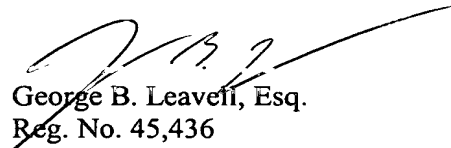Alexandria, VA 22313-1450

Dear Sir:

The references listed in the attached PTO Form 1449 may be material to examination of the above-identified patent application. Applicants submit these references in compliance with their duty of disclosure pursuant to 37 CFR §§ 1.56 and 1.97. The Examiner is requested to consider these references and to acknowledge such consideration by initialing the attached PTO Form 1449 at the appropriate locations.

Applicants state that each item of information listed in the attached PTO Form 1449 was cited in a communication in a counterpart international application not more than three months prior to the filing of this statement. For the Examiner's use and information, a copy of the International Search Report in the corresponding international application is attached.

Applicant believes no fee is due with this filing, however the Commissioner is authorized to charge any fees that may be due to our Deposit Account No. 50-0805 (Order No. LAM2P425).

Respectfully submitted,
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Substitute for form 1449/PTO	Complete if Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT *(Use as many sheets as necessary)*	Application Number	10/606,022
	Filing Date	June 24, 2003
	First Named Inventor	Boyd
	Art Unit	1746
	Examiner Name	Unassigned

Sheet	1	of	1	Attorney Docket Number	LAM2P425

U.S. Patent Documents

Examiner Initials	Cite No.[1]	Document Number — Number-Kind Code [2] (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, where Relevant Passages or Relevant Figures Appear
	A	6,230,722	May 15, 2001	Kenichi et al.	
	B				
	C				
	D				
	E				
	F				
	G				
	H				

Foreign Patent Documents

Examiner Initial	Cite No.[1]	Foreign Patent Document No. — Country Code[3]-Number-[4]Kind Code [5](if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, where Relevant Passages or Relevant Figures Appear	T[6]
	I	WO 02/32825	Apr 25, 2002	The Regents of the University of California		☐
	J					☐
	K					☐
	L					☐
	M					☐

Non Patent Literature Documents

Examiner Initial	Cite No.	Include name of author (in CAPTIAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published
	N	International Search Report
	O	
	P	
	Q	

Examiner Signature		Date Considered	

Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

[1]Applicant's unique citation designation number (optional). [2]See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. [3]Enter Office that issued the document, by two-letter code (WIPO Standard ST.3). [4]For Japanese patent documents, the indication of the year of the reign of Emperor must precede the serial number of the patent document. [5]Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. [6]Applicant is to place a check mark here if English language translation is attached.